

Search Notes

Application/Control No.

10/717,284

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

TAFT ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	10-11-05	<i>[Signature]</i>